

N-Channel 80 V (D-S) MOSFET

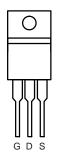
PRODUCT SUMMARY				
V _{DS}	80	V		
$R_{DS(on)} V_{GS} = 10 V$	6	mΩ		
$R_{DS(on)}$ $V_{GS} = 4.5 \text{ V}$	14	mΩ		
I _D	120	Α		
Configuration	Single			

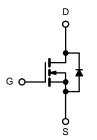
FEATURES

- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless	otherwise note	d)	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	80	V	
Gate-Source Voltage		V _{GS}	± 20	\ \ \
	T _C = 25 °C		120	
Ocation and Ducin Organization (T. 150 °C)	T _C = 70 °C	_	85 ^a	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	28.6 ^{b, c}	
	T _A = 70 °C		24.9 ^{b, c}	_
Pulsed Drain Current (t = 100 μs)	I _{DM}	350	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	,	100	
	T _A = 25 °C	I _S	4.5 ^{b, c}	
Single Pulse Avalanche Current	. 0.1!!	I _{AS}	30	
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	45	mJ
Maximum Power Dissipation	T _C = 25 °C		180	
	T _C = 70 °C		120	147
	T _A = 25 °C	P _D	5 ^{b, c}	W
	T _A = 70 °C		3.2 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	***
Soldering Recommendations (Peak Temperature	Ţ.	260	°C	

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R_{thJA}	20	25	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	1.5	2.0	C/VV

Notes

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. The TO-220 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.



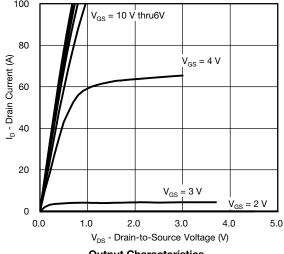
Dougnastes	Comple el	Tool Consistence	N.A.:	T	NA	1122	
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	.,	V 0.V 1 0.50 A		T	1	1 ,,	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V	
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	I _D = 250 μA		37		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	<u> </u>		- 6.1			
Gate-Source Threshold Voltage	V _{GS(th})	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.5		4.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA	
	.033	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	P., .	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	85			Α	
		$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		6			
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 6 \text{ V}, I_D = 15 \text{ A}$		10		mΩ	
		$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		14			
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 10 \text{ V}, I_D = 20 \text{ A}$		60		S	
Dynamic ^b							
Input Capacitance	C _{iss}			7000		pF	
Output Capacitance	C _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1400			
Reverse Transfer Capacitance	C _{rss}			560			
	Qg	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5		nC	
Total Gate Charge		$V_{DS} = 40 \text{ V}, V_{GS} = 6 \text{ V}, I_D = 10 \text{ A}$		22			
				17.1			
Gate-Source Charge	Q _{gs}	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		5.3			
Gate-Drain Charge	Q _{gd}			7.3			
Output Charge	Q _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		57	86		
Gate Resistance	R _g	f = 1 MHz	0.5	1.3	2	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	$V_{DD} = 40 \text{ V}, R_1 = 4 \Omega$		8	16	1	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_q = 1 \Omega$		32	64	1	
Fall Time	t _f	Ç		7	14	1	
Turn-On Delay Time	t _{d(on)}			14	28	ns	
Rise Time	t _r	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$		11	22	- - -	
Turn-Off DelayTime	t _{d(off)}	$V_{DD} = 40 \text{ V}, R_L = 4.52$ $I_D \cong 10 \text{ A}, V_{GEN} = 6.0 \text{ V}, R_a = 1 \Omega$		30	60		
Fall Time	t _f	D ALIV y		8	16		
Drain-Source Body Diode Characteristic					10		
Continuous Source-Drain Diode Current		T _C = 25 °C		75			
Pulse Diode Forward Current (t = 100 µs)	l _S	10 - 23 0		150	 	A	
Body Diode Voltage	I _{SM}	I _S = 5 A		0.76	1.1	V	
	V _{SD}	IS = SI				+	
Body Diode Reverse Recovery Time	t _{rr}			38	75	ns	
Body Diode Reverse Recovery Charge Reverse Recovery Fall Time	Q _{rr}	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		36 19	70	nC	
	. + 1	•		1 10		1	

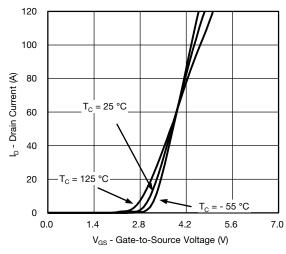
Notes

- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

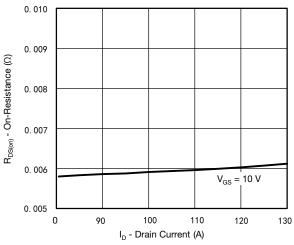


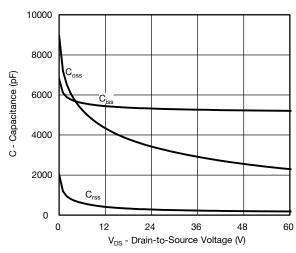






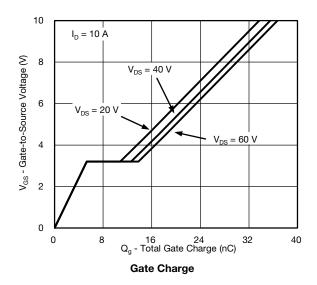


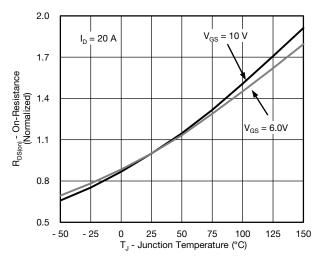




On-Resistance vs. Drain Current

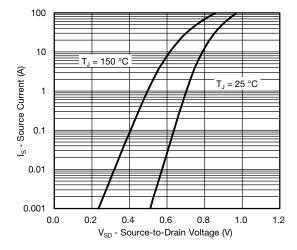
Capacitance



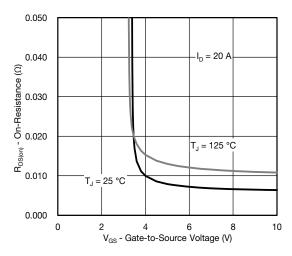


On-Resistance vs. Junction Temperature

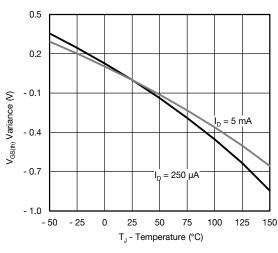




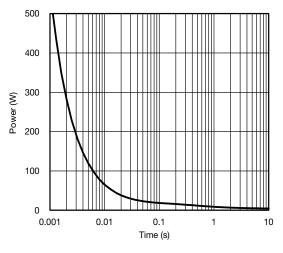
Source-Drain Diode Forward Voltage



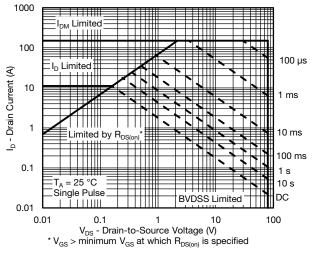
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

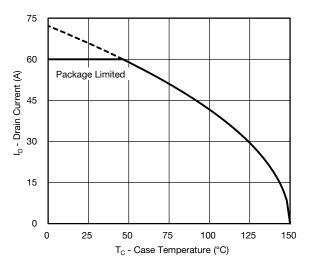


Single Pulse Power, Junction-to-Ambient

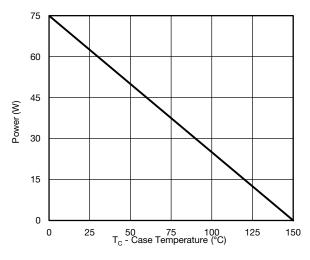


Safe Operating Area, Junction-to-Ambient

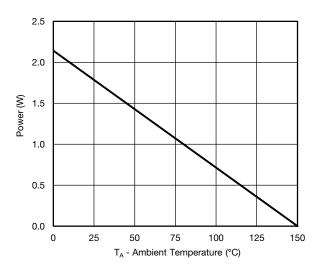




Current Derating*



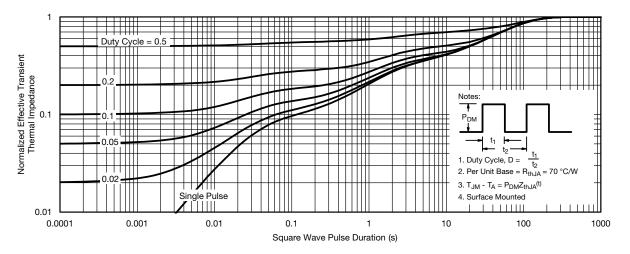




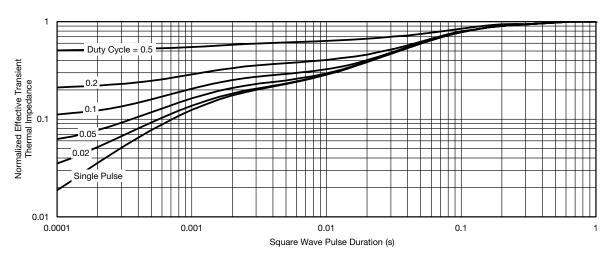
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





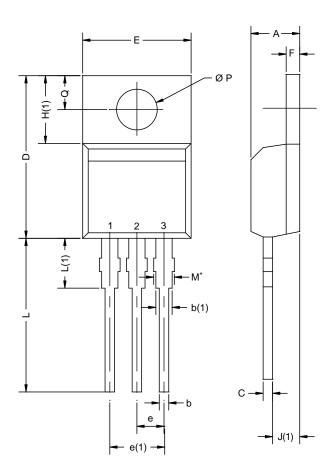
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



TO-220AB



	MILLIMETERS		INC	CHES		
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
Е	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØР	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N, 08-Oct-12						

ECN: X12-0208-Rev. N, 08-0 DWG: 5471

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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